

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination LOVE ET AL.	
			10/724,278	Examiner <i>MC 10/25/01</i>	Art Unit 2874
			Michelle R. Connelly-Cushwa	2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	Stockle et al., "High-quality near-field optical probes by tube etching", Applied Physics Letters, Volumn 75, Number 2, 12 July 1999, pages 160-162.		
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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